



November 28th-29th 2019 | Grenoble

the event dedicated to the material characterisation for industry

Platform for Advanced Characterisation Grenoble PAC-G

Supported by the French government under the IRT Nanoelec Investissements d'avenir economic stimulus package, (reference ANR-10-AIRT-05).

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With the support of:



The PAC-G: an unique framework

Single entry point for characterization services,
dedicated to micro- and nano-electronics industry



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The ESRF: the most intense synchrotron generated light in the world



ESRF – Grenoble, France

A research facility unique worldwide

- ✓ **N.1 in scientific output**
- ✓ **Over 25000 articles** referencing the ESRF
- ✓ **6,500 scientific visitors** every year including **4,000 users**
- ✓ **2,000 proposals** per year: **900 accepted**, 1,550 experimental sessions
- ✓ **30% of the research** involves **industrial developments**

The PAC-G: an unique framework

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The ILL: ILL is the most intense neutron source in the world



1400 users from an active community of 12 000 scientists



850 experiments/year



650 publications/year



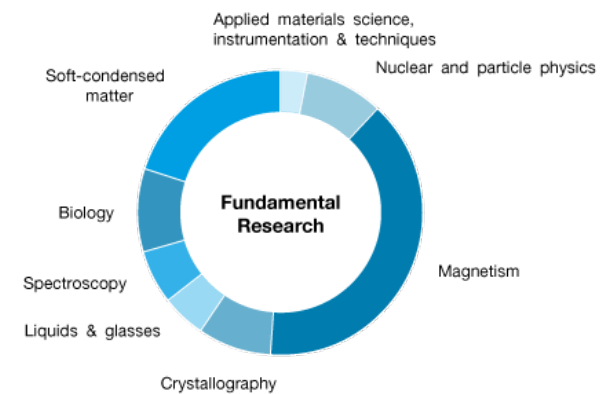
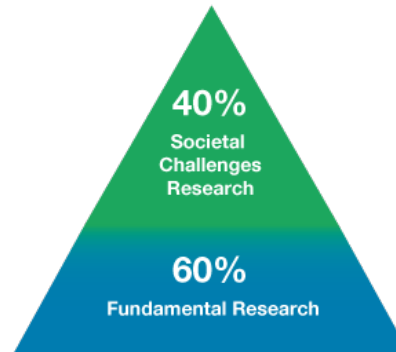
38 countries



28 instruments + 10 CRG



4 cycles of 50 days/year



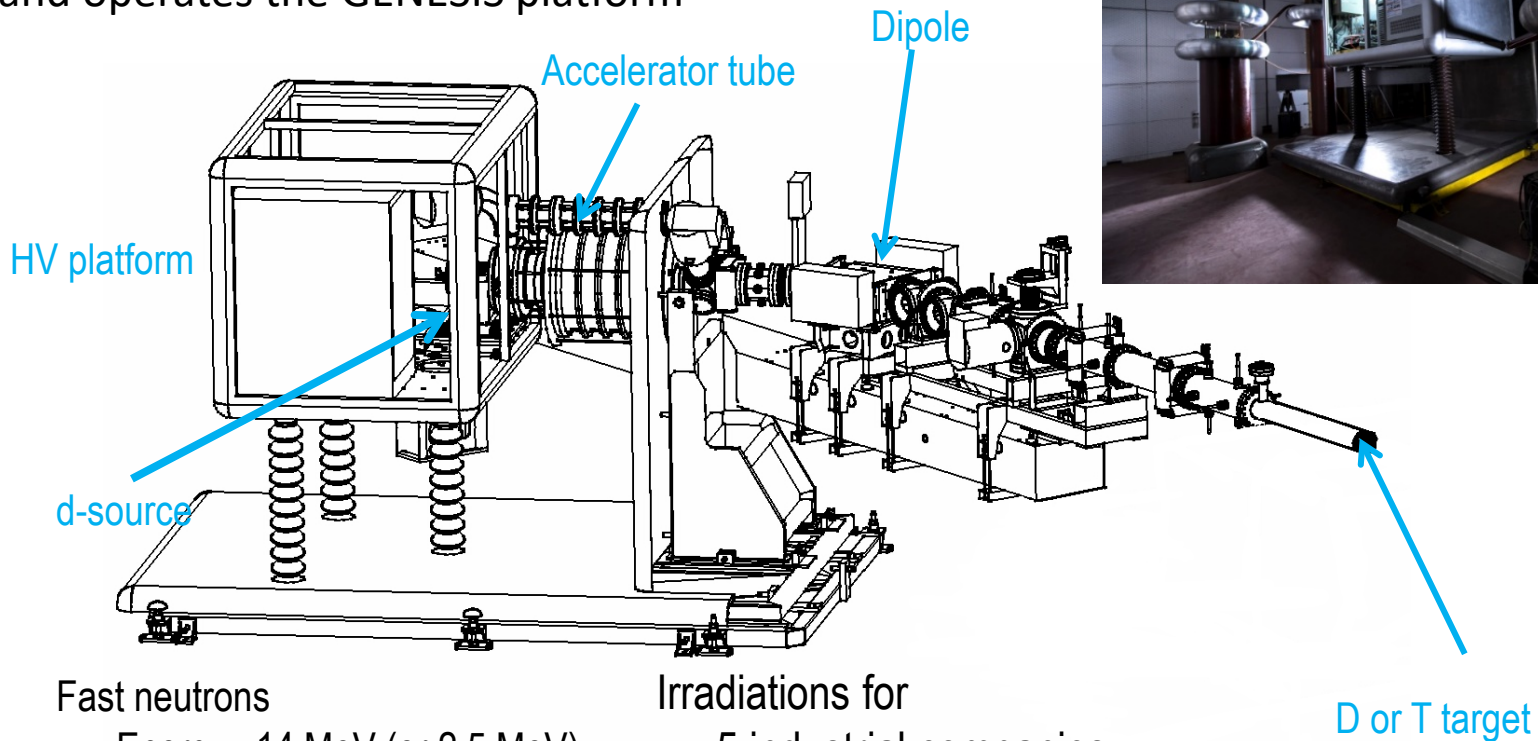
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LPSC/GENESIS : High energy neutrons source

LPSC is a joint research unit CNRS/IN2P3 - UGA - G INP and operates the GENESIS platform



Fast neutrons

- Energy : 14 MeV (or 2.5 MeV)
- Flux up to $5 \cdot 10^7 \text{ n} \cdot \text{s}^{-1} \cdot \text{cm}^{-2}$

Irradiations for

- 5 industrial companies
- Research labs and universities

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Single entry point for characterization services,
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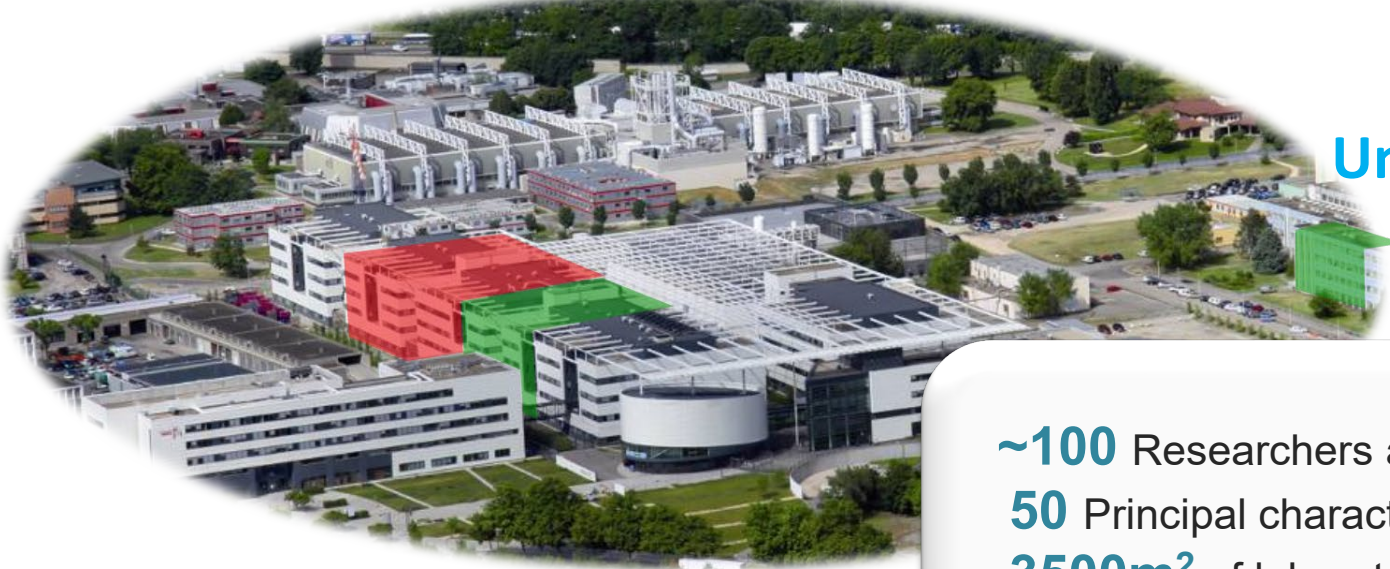
PFNC... at a glance

Created in **2006**...

... within the **Minatec Campus**,

Federation of the resources of three Institutes based at CEA/Grenoble

- **leti** (DRT/Laboratory for Electronics & Information Technology)
- **liten** (DRT/Laboratory for Innovation in New Energy Technologies & Nanomaterials)
- (DSM/Institute for Nanoscience & Cryogenics)



Unique in Europe

~100 Researchers and Technicians,
50 Principal characterisation tools,
3500m² of laboratories,
1 partnership with SERMA Tech

PFNC: Complementary techniques

8 Centers of Competences

**μXRD
Synchr.**



**X-Ray
Analysis**

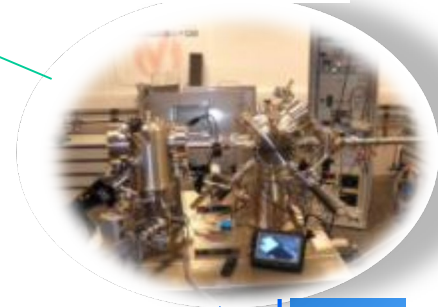
**Sample
Preparation**

**Magnetic
Resonance**



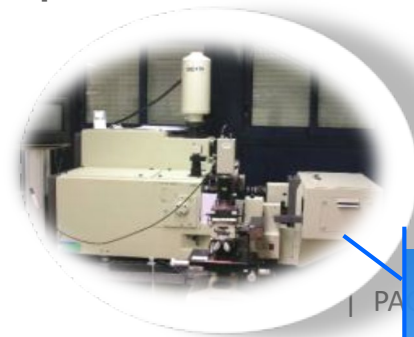
**RMN
DNP**

Scanning Probe



**SSRM
SCM
KFM**

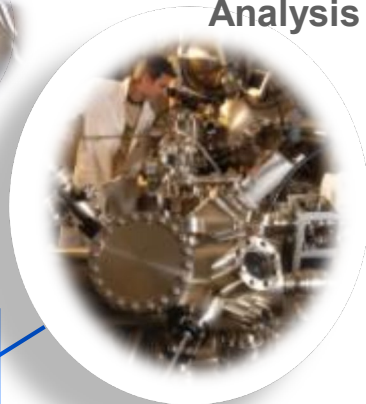
Optics



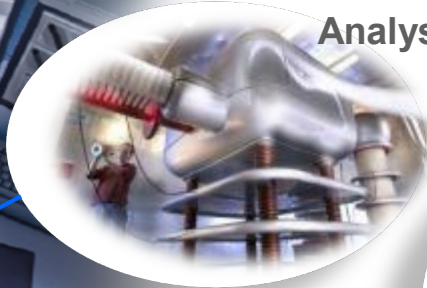
**Ellipso, FTIR,
PL, cathodo...**

**FIB-DB
Polishing,
chemical prep...**

**Surface
Analysis**



**Ion Beam
Analysis**



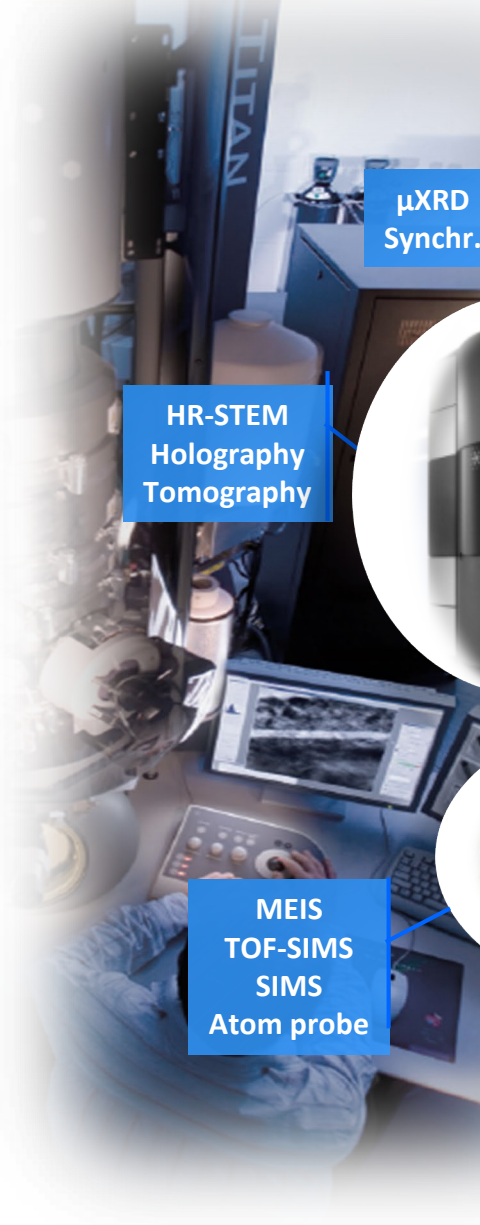
**MXPS
X-PEEM
Nano-Auger**

**Electron
Microscopy**



**HR-STEM
Holography
Tomography**

**MEIS
TOF-SIMS
SIMS
Atom probe**



Platform for Advanced Characterization Grenoble (PAC-G)

Irradiation services

High energy neutrons

Low energy neutrons

Synchrotron X-rays

Fast neutrons irradiation (14 Mev)

Thermal/cold neutrons (25meV)

Pulsed X-ray microbeam
Focalised X-ray nano-beam

Imaging & failure analysis

Synchrotron X-ray micro-imaging

Synchrotron X-ray nano-imaging

Neutron imaging

Micro-tomography
Ultra-fast radiography

Nano-tomography

Micro-tomography
Neutron and X-ray micro-tomography

Physical/chemical characterisation

Strain/Stress measurements

Structural characterization

Interface characterization

K-map
Rocking Curve Imaging

XRD
XRDI
SAXS
SANS

X-ray and Neutron Reflectivity (XRR, NR)

Why use large-scale facilities

Non-destructive testing

In-situ and/or In-operando investigations
(sample environments)

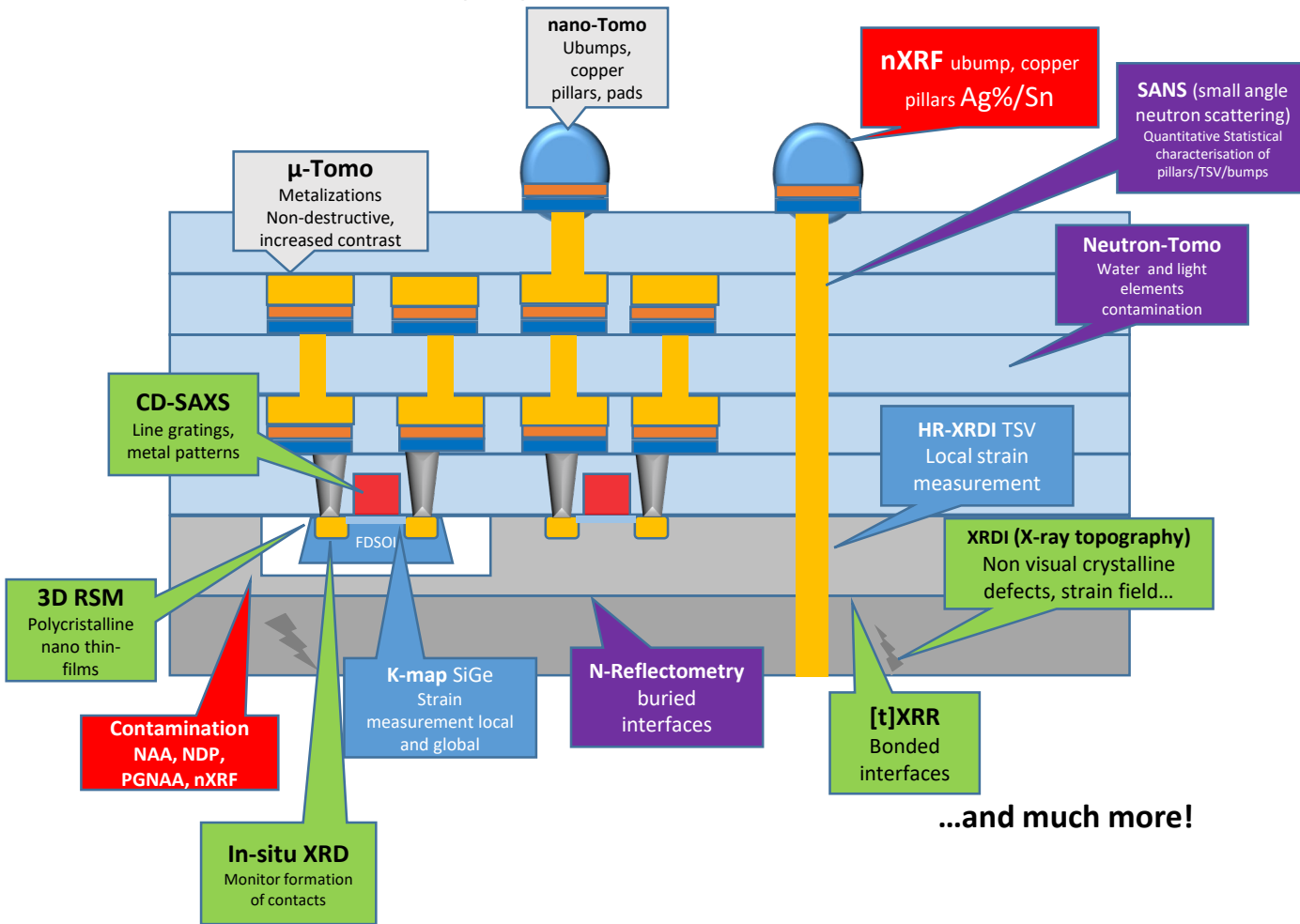
Statistical characterisations
(fast acquisition time)

Very high spatial and time resolutions

Unmatched detection capabilities



What applications?



List of techniques

Physical and Chemical Characterisation

- X-ray white beam topography
- X-ray monochromatic beam topography
- X-ray rocking curve imaging
- X-ray rocking curve imaging + Section topography
- X-ray high resolution rocking curve imaging
- X-ray diffraction (in-situ / ex-situ)
- X-ray reflectivity XRR
- Reciprocal Space mapping 3D (3D RSM)
- CD-SAXS
- Neutron Reflectivity
- k-map
- High resolution diffraction imaging (HR-XRDI)
- Nano fluorescence

Imaging techniques

- X-ray micro tomography
- X-ray nano tomography
- Neutron tomography
- Neutron + X-ray tomography
- Ultrafast radiography

Irradiation for SEE testing

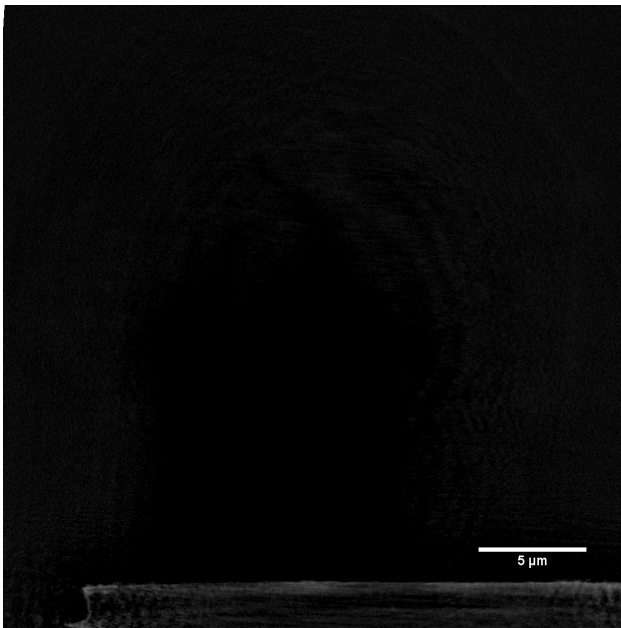
- Fast neutrons irradiation
- Thermal neutrons irradiation
- Synchrotron X-ray Irradiation

...and much more!

Application in advanced packaging

Synchrotron X-ray nano tomography

Looking for intermetallic alloys, voids and defects in Cu-pillars (10, 25 and 50 μ m) non-destructively



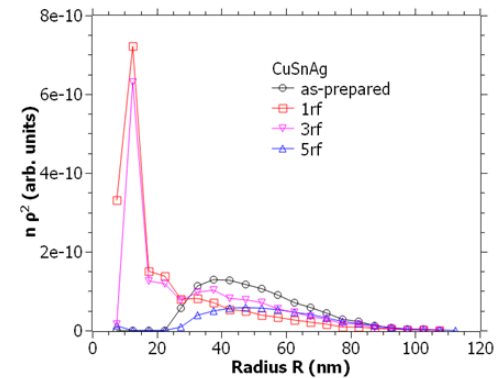
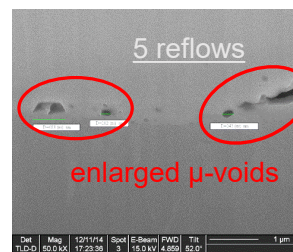
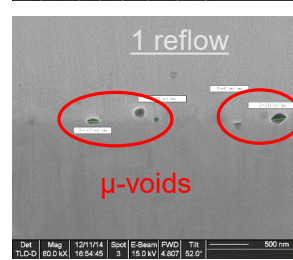
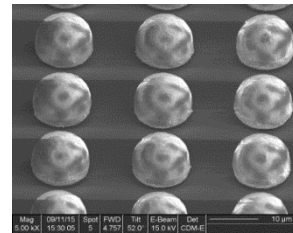
World record resolution 30nm

A. FRACZKIEWICZ- "Développement de la tomographie par rayons X en synchrotron pour l'industrie : application à l'analyse de défaillance en intégration 3D - Grenoble, 2017"

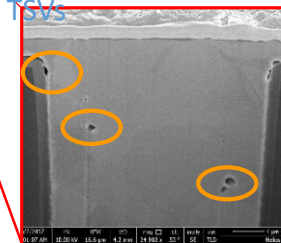
Innovative solutions to characterization challenges

Statistical analysis of voids in several Cu-pillars.

Small Angle Neutron Scattering



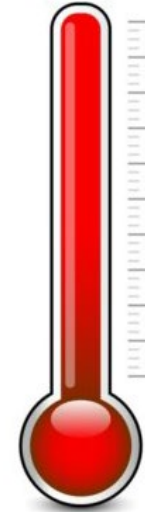
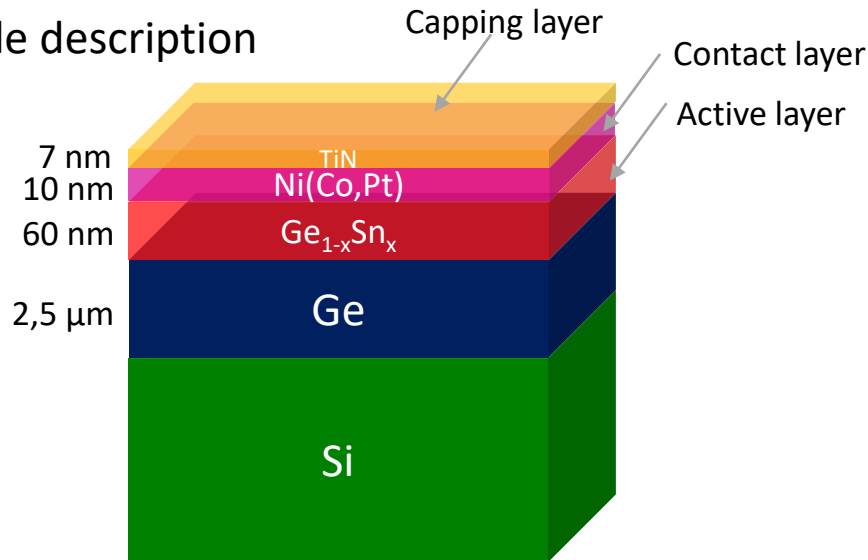
Applicable to similar problems: defects in TSVs



In-situ diffraction: monitoring of solid-state reaction kinetic of Ni (Co, Pt) with Ge(Sn)/Si

Objective: Study the alloy formation (NiCoPtGeSn) to improve the ohmic contact between the active layer and the TiN

Sample description



Several experiments on several samples:

Samples:

- NiPt/GeSn(10%)
- Ni/GeSn(6%)
- Ni/GeSn(10%)
- Ni/Ge
- **NiCo/GeSn(10%)**

- RTA – rapid thermal annealing
- Slow heating
- isothermal

Solid-state reaction between contact layer Ni(Co,Pt) and semiconductor $Ge_{1-x}Sn_x \rightarrow$ source & drain contacts

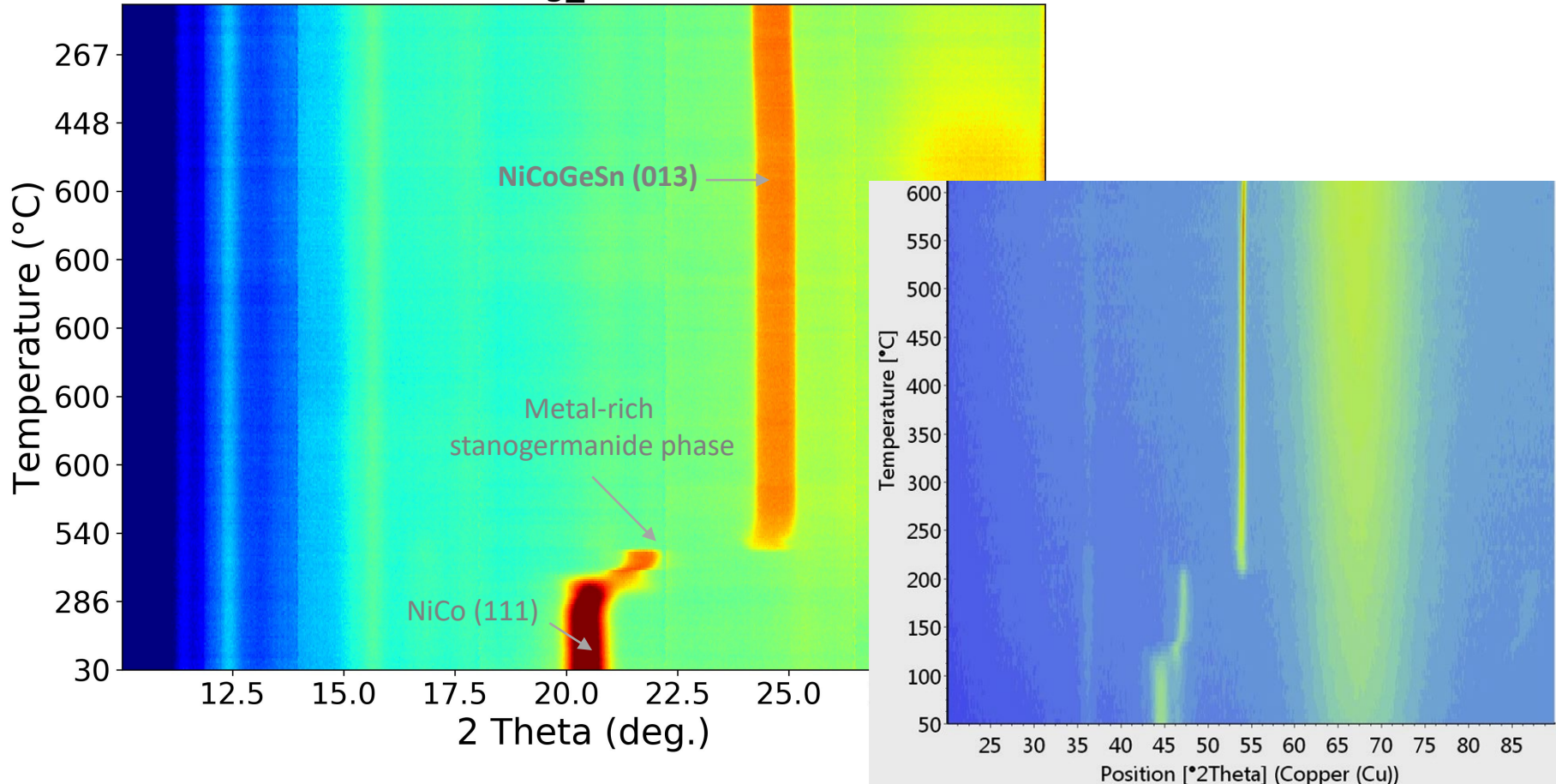
In-situ diffraction: monitoring of solid-state reaction kinetic of Ni (Co, Pt) with Ge(Sn)/Si

In-situ diffraction of NiCo/GeSn(10%) – fast heating



In-situ diffraction: monitoring of solid-state reaction kinetic of Ni (Co, Pt) with Ge(Sn)/Si

fastHeating_NiCoGeSn10



Lab measurement, copper source, 7 minutes per temperature, 13 hours for this map

Key take-aways

- The PAC-G is a service platform dedicated to the microelectronics industry using the large scale research facilities of Grenoble (ESRF, ILL, LPSC) with the support of the CEA Leti's PFNC
- More than 20 services are available through this platform and dedicated personnel insure customer satisfaction
- The PAC-G has its first industrial collaboration agreement with SERMA Technologies, a well established company in the electronics sector



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Thank you!

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